

LMU – Cluster Universe Stefan Rummel

Power supply for the BELLE II PXD

5th International Workshop on DEPFET Detectors and Applications

29.09-30.09. Valencia





Overview

- News from LMU
- PS project schedule
- Requirement analysis
 - Parameter definitions currents, voltages
 - Transient behavior
 - Radiation, B-Field
 - Position of PS
- Regulation over long distances and test structures
- PS Slowcontrol





- Since July member of the BELLE II collaboration
- Regular EVO meeting on PS development

•Group is growing – Electronics Engineer Andreas Seiler has joint us in of August

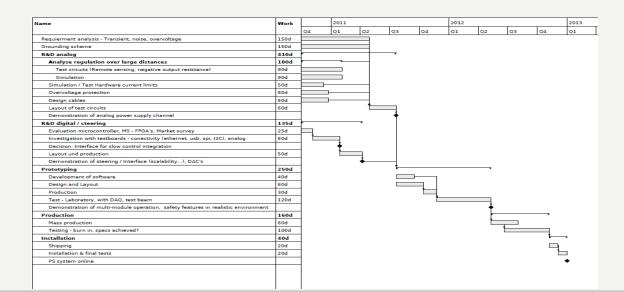
- Setup of electronics lab is almost finished
 - Mixed signal oscilloscope / current probe
 - AC/DC active load
 - Signal generator, 6.5 digit DMM, PS's
 - Soldering equipment
 - Layout program Altium Designer

- ...





- Important milestones:
 - Demonstration regulation under realistic conditions (cable, distance, noise, transients...)
 - Demonstrate connectivity, steering of analog part
 - Prototype: demonstration of multi module operation, safety features
 - Prototype for testing of ladders in 06/2012
 - Commissioning beginning of 2013







Requirements update



Position of PS



- Baseline: Outside of detector (same as DHH)
- Moderate distance of ~15m from IP
- Primary supplies in electronics hut 30m from IP





- Magnetic field ~10 Gaus (~ mT)
- Estimate on radiation based on outer layer of KLM to our current best knowledge 0.48Hz/cm2
- •Back on the envelope calculation gives:
- → 50rad over 5 years including factor 100 safety (assuming MIPS)

- Radiation and magnetic field seem to be no problem outside of the detector
- Commercial components should do the job





- High voltage increased from 40V to 80V due to lower resistivity silicon, punch through biasing and thicker detector
- For calibration propose the Gate voltage must be variable from threshold to nominal value (~ V_SOURCE to V_SOURCE + 6V)
- Ganging has also impact on power consumption:
 - I_SOURCE doubles from 100mA to 200mA
 - Currents of steering voltages
 - Rest should be stable

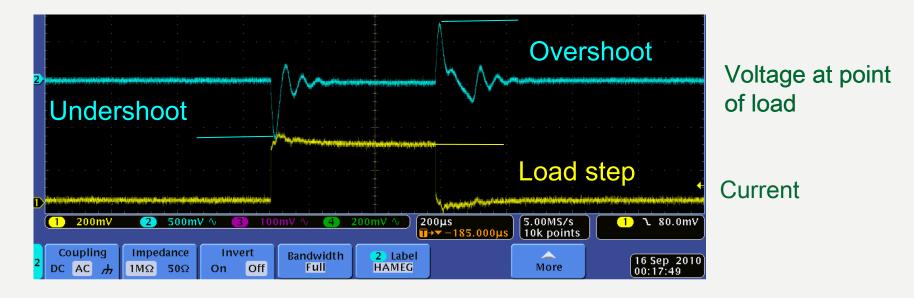


Transient behaviour



No regulation is ideal

- DC regulation not perfect
- Load steps lead to temporary deviations

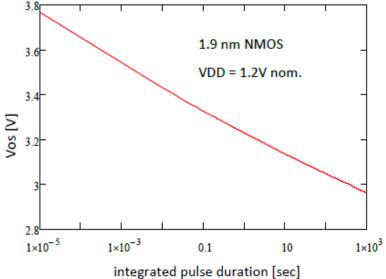


- Deviations need to be controlled:
 - Overshoots can damage oxide
 - Undershoot may lead to loss of data



- two DHP voltage domains: core with thin gate oxide and IO with thick gate oxide MOSFETs
- recommended values according to the equations in the IBM CMOS 90nm (CMS9FLP) Technology Design Manual for gate dielectric reliability voltage limits:
 - Vdc max: maximum static DC voltage (@ 100.000 operation hours, T = 30°C)
 - Vos 1%: maximum overshoot for periodic signals, calculated for overshoot pulse width equal to 1% cycle time
 - overshoot due to power switching has much less duty cycle
 - transient stress damage is a product of pulse duration and the number of events = integrated pulse duration

	Tox [nm]	V nom [V]	Vdc max [V]	Vos 1% [V]
Thin oxide	1.9	1.2	1.6	2.7
Thick oxide	5.2	1.8	3.5	4.2





- •Assuming: 50us overshoot, 1 overshoot/run, 10min/run
- \rightarrow Duty cycle <10⁻⁷
- Numbers at 30degC
- Need some room for radiation induced damage

•"Vos 1%" should be conservative – but some doubts remain...



Regulation over long distances





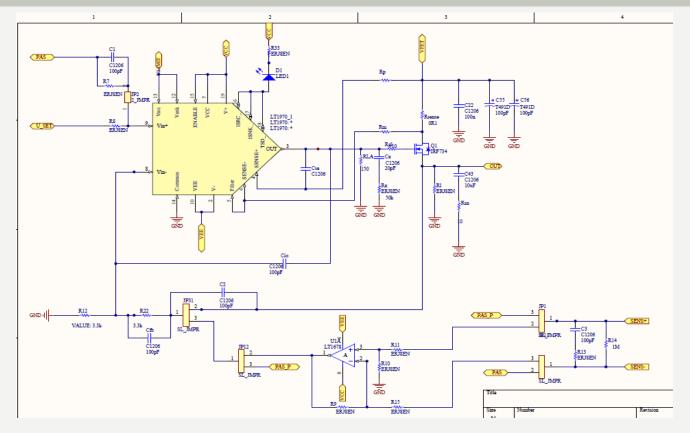
Regulation over large distaces



- Twofold approach:
 - Simulation (Matlab, Spice)
 - Experimental
 - Test regulator
 - Long cables







- •Discrete pass element linear regulator
- •Hardware current limit
- •Various ways of remote sensing no, passive, active

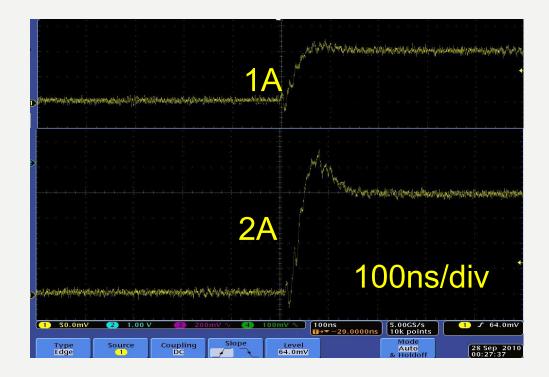




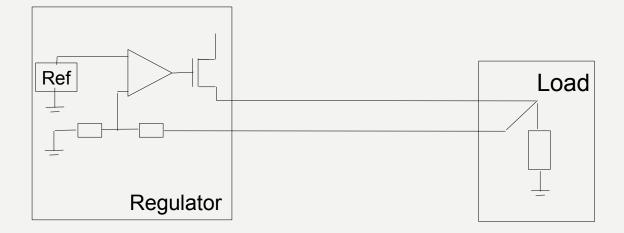
- Why LT1970?
 - Integrated current limit amplifier hardware current limit
 - Enable pin and thermal shutdown
 - Specified from 5V to 36V supply voltage
 - >500mA output current
 - Also used in NI PXI-4110 PS
 - Very low dropout voltage
 - Output can be set down to 0V
 - Power consuming part separated from "intelligence"
 - FETS with low thermal resistance packages available → easy thermal management
 - NMOS source at output → good PSSR
 - Precise current sensing on "high side" no additional resistor between load and regulator
 - Can be easily configured as current sink
 - Need additional voltage (few mA) to drive the FET
- Allows a unified design which serves for ALL voltages (except HV)



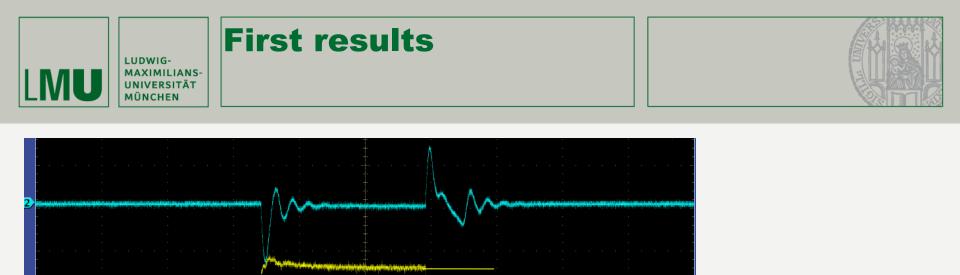
- Circuit to simulate fast transients (few Amps @ 50ns risetime)
- Long cables in AWG12/18 as TDR cable
- Test bench is available







- Load and regulator share common ground
- Realistic delays



An interesting the second

200µs ∎→▼ –185.000µs

2 Label

HAMEG

2.5A load step

1 **1** 80.0mV

16 Sep 2010 00:17:49

5.00MS/s 10k points

 \wedge

More

• Wire: 7.5m, AWG 18 \rightarrow 170m Ω

On

Invert

Off

Bandwidth

Full

• (0.1/2.6)A load step

2

Impedance

1MΩ 50Ω

Overshoot: 700mV for 20us

500mV ∿

200mV

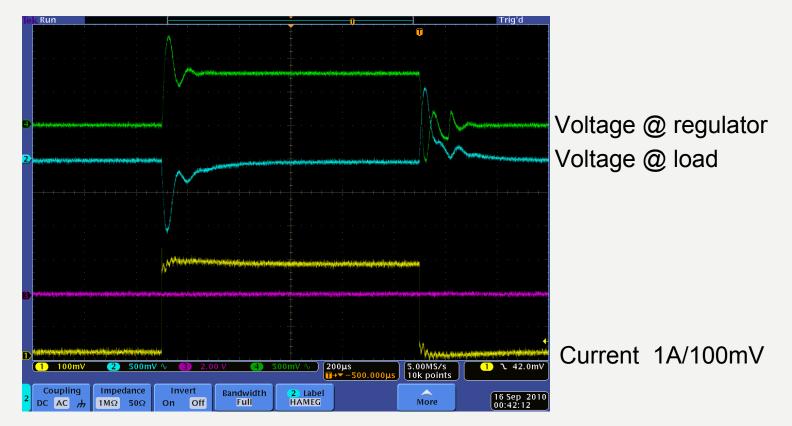
Coupling

DC AC H



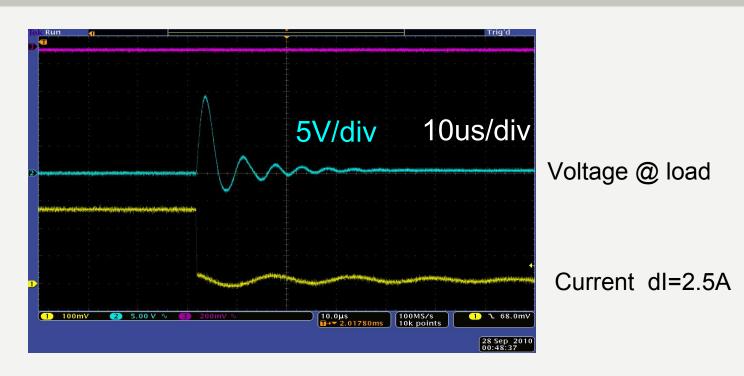
First results



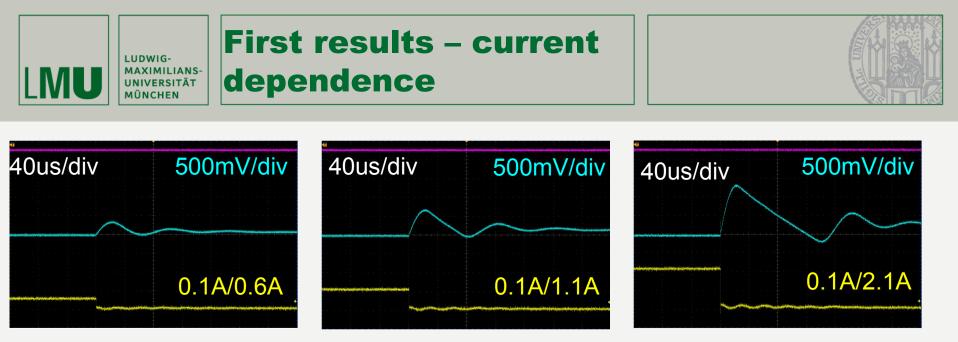


- Wire: 15m, AWG 18, 320mΩ
- (0.1/2.6)A load step
- Overshoot: 1V for 20us
- Increase of 40% compared to 7.5m



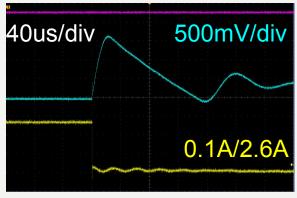


- Wire: 15m, AWG 18, 320mΩ
- (0.1/2.6)A load step
- Load capacity 100nF
- Overshoot: ~14V



"DHP"

- Wire: 15m, AWG 18, $320m\Omega$
- Load capacity 10uF
- \rightarrow Overshoot scales with current





Comments/ Next steps



•Up to now regulator behaved quite stable (100nF - 50uF ceramic capacitors, with $100m\Omega$ ESR, various cable length)

- •Get more experience with the regulator:
 - Region of stability
 - Comprehensive DC characterization
 - Noise
- •Improve sensing:
 - Reduce DC error: Active sense amplifier with high input impedance
 - Test impact of termination (at HF)
- Test current limit
- Include flex (prototype) into tests



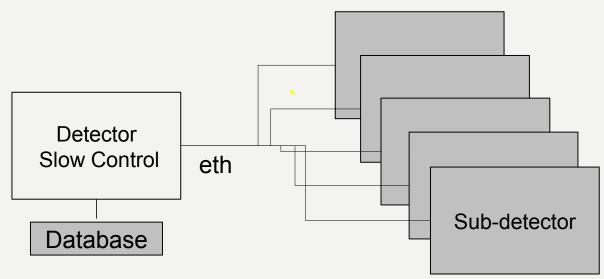
Slow control







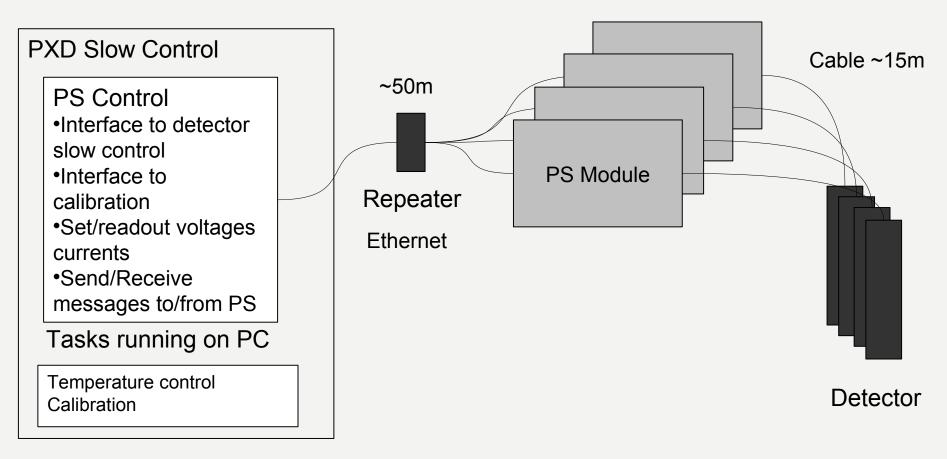
- Slow control
 - Control of services (power, cooling)
 - Logging of temperatures, voltages, currents, calibration data...



- •Distributed system
- ·Connected via Ethernet
- ·Each sub-detector provides a producer





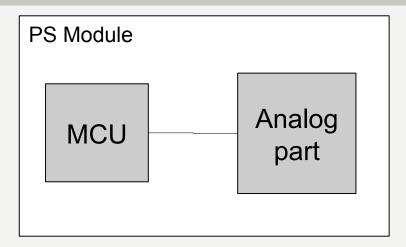




Power supply module



- Tasks on MCU
 - Continuous reporting to PS control (~10Hz)
 - Error handling
 - Error messages in case of failures
 - Receive messages from control
 - Readout currents/voltages
 - Set voltages and currents
 - Start and stop sequences
- Looked into various MCU architectures identified ARM Cortex e.g. STM32F as interesting



Interface to outer world ETHInterface to analog section (SPI, I2C)





- TUM computer science chair for "Robotics and Embedded Systems" with strong background in safety critical systems, embedded systems, real time applications...
- First exploratory discussion with Prof. Knoll
- •Showed interests in the software part of the PS slow control (embedded part and PC)



Open issue



- Overvoltage protection
 - For low currents no problem can be made on PS level
 - Wishlist: High current OVP on patch panel
 - Radhard solution requiered
 - Currently looking into ATLAS-SCT solution
- Maybe we can relax this:
 - DHP core: Vdc max-Vnom = 400mV
 - DHP IO: Vdc max-Vnom = 1.7V
 - PS voltage at 1A: Vnom+300mV (AWG12 15m + 150mOhm flex)
 - → OVP @ PS is able to limit the voltage to safe regions





- Requirements on voltages, transient behavior are converging
- PS development at LMU has started, first circuitry tested
- Results under realistic conditions cable length, various loads can be expected till next B2GM





Backup



Simulation of regulator response with delays
Delay at least L/c c~0.6c0 → 55ns for 10m cable
Investigated model:

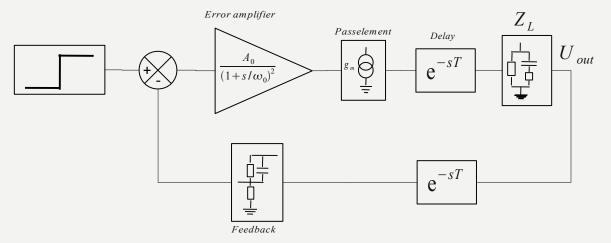


Figure of merit:

- Step response
- Settling time, over shoot, rise time...
- Phase margin

